



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No. : 10/612,174 **Confirmation No.:** 5221

Applicants: Robert K. Reich et al.

Filed: July 2, 2003

TC/A.U.: 2826

Examiner: K. Quinto

Docket No.: MIT8806L

For: High-Speed, High-Sensitivity
Charge-Coupled Device

COMMISSIONER FOR PATENTS
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I hereby certify that this correspondence is
being deposited on the date shown below with the
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September 14, 2005
[Signature]

DECLARATION UNDER 37 C.F.R. §1.132
THAT THE CO-INVENTORS NAMED IN THIS APPLICATION
CONCEIVED OR INVENTED THE SUBJECT MATTER OF THIS
APPLICATION THAT IS DISCLOSED IN A CITED PUBLICATION

1. The Examiner has cited the publication, "High-Fill-Factor, Burst-Frame-Rate Charge-Coupled Device," by Reich, O'Mara, Young, Loomis, Rathman, Craig, Watson, Ulibarri, and Kosicki, International Electron Device Meeting and IEDM Technical Digest, pp. 567-570, December 2001, against the claims of the instant application as prior art under 35 U.S.C. §102(a).

2. I am named as a co-inventor on the instant application.

3. I hereby declare as a named co-inventor on the instant application, and signing below, that:

A. The subject matter of the Reich et al. publication identified above was conceived and/or invented by the inventors named on the instant application and that the inventorship of the instant application is correct;

B. The co-authors of the Reich publication identified above that are not named as co-inventors on the instant application did not contribute to conception or invention of the invention claimed in the instant application, and instead, carried out activities related to the fabrication and testing of the invention under the supervision of the inventors, or defined a need for the invention; specifically:

a. D.M. O'Mara conducted testing and characterization of CCD devices;

b. D.J. Young was a fabrication process engineer responsible for CCD fabrication processes;

c. A.H. Loomis was a fabrication process engineer responsible for CCD fabrication processes;

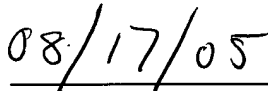
d. D.M. Craig wrote software for conducting testing and characterization of CCD devices;

e. S.A. Watson defined desired CCD performance characteristics for addressing specific applications and requested design solutions; and

f. M.D. Ulibarri defined desired CCD performance characteristics for addressing specific applications and requested design solutions.

5. I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under 18 U.S.C. 1001 and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.


Robert K. Reich


Date